



# TestForum 2017

Sokos Hotel Flamingo, Vantaa, Helsinki, Finland  
November 28<sup>th</sup> - 29<sup>th</sup>, 2017

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## Test Forum 2017 Local Organizer

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## Call for Papers / Presentations

The 2-day TestForum 2017, the 18<sup>th</sup> event in the series, is the major event for Test professionals in the Nordic area and the Baltic states. Every year the TestForum is attended by key people from the industry's test community as well as by international vendors of test and measurement equipment and solutions.

This year the event will take place in Helsinki.

Nordic Test Forum hereby cordially invites you to participate and submit your contribution to TestForum 2017, which includes (but is not limited to) the following topics:

- *Functional Test*
- *Boundary Scan*
- *Embedded Instruments*
- *RF Testing*
- *AOI / AXI / SPI*
- *ICT / Flying Probe*
- *Test economics*
- *Power Test*
- *Fixturing/Interfaces*
- *Future technology trends and test challenges*
- *Best practices in manufacturing test*
- *ASIC: BIST / Mixed-signal / IDDQ / IDDT*
- *Board test SW, BIST, diagnostics*
- *Quality methods and tools*
- *Preventive test / Prognostics*
- *Design to Test transfer / Design for Test*
- *ESD*
- *Test efficiency and optimization*
- *Data acquisition / collection / analysis*

## Submissions

TestForum seeks full papers and/or presentations in the area of test of electronics, including *R&D, Application Contributions, Best Practices, Emerging Ideas*, etc. You are welcome to submit contributions also outside the above topics as long as they stay within the field of electronics test. Focus shall be on new and upcoming challenges, opportunities, techniques and best practices in electronics test technology rather than on particular products.

## Proceedings

The accepted contributions of authors that wish to provide the corresponding materials will be delivered in electronic format at the Nordic Test Forum event.

## The Format of the Event

- The event format will be a two-day workshop and a small exhibition attached to it.
- November 27<sup>th</sup> in the evening there is the AGM of the NTF.
- The mix of presentations will decide the number of sessions.
- The presentations will be 30 minutes each: 25 minutes of speech and 5 minutes for questions and comments.
- In the exhibition, attendees will have a chance to see the latest equipment and talk to exhibitors.

## Key Dates

- Abstract submission: **16<sup>th</sup> June 2017**
- Notification of acceptance: **28<sup>th</sup> July 2017**
- Conference registration: **1<sup>st</sup> August 2017**
- Presentation slides: **3<sup>rd</sup> November 2017**

## Further Information and Submissions

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Visit the NTF web pages at:  
<http://www.nordicestforum.org>

